

Notice of References CitedApplication/Control No.
09/452,749Applicant(s)/Patent Under
Reexamination
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*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
	A	US-5,157,466-	10-1992	Char et al.	357	5
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		Country Code-Number-Kind Code	MM-YYYY				
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shnirman et al. Quantum measuremetns performed with a single-electron transistor, 1998, Phys. Rev. B V57, pp15400-15407
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.